

Notice of References Cited

Application/Control No.

09/870,280

Applicant(s)/Patent Under
Reexamination
SHAKERI ET AL.

Examiner

Thomas H. Stevens

Art Unit

2123

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,475,851	12-1995	Kodosky et al.	715/763
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	V	Winter et al., "Blockism--Application of Non-Linear Modelling and Simulation in Fuzzy Control System Design" IEEE 1994 pg. 1337-1342				
	W	Ghoshal et al., "Multi-signal Modeling for Diagnosis, FMECA, and Reliability" 1998 IEEE pg. 3026-3031				
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.